

Notice of References Cited	Application/Control No. 09/944,501	Applicant(s)/Patent Under Reexamination KON ET AL.	
	Examiner Cristina Owen Sherr	Art Unit 3621	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,990,684	01-2006	Futamura et al.	726/18
*	C	US-7,100,044	08-2006	Watanabe et al.	713/156
*	D	US-6,697,947	02-2004	Matyas et al.	713/182
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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